

Octal Buffer/Line Drivers, 3-State

CD74AC/ACT540 - Inverting CD74AC/ACT541 - Non-Inverting

Type Features:

- Buffered inputs
- Typical propagation delay: 4.5 ns @ V_{CC} = 5 V, T_A = 25° C, C_L = 50 pF

The CD54/74AC540, -541, and CD54/74ACT540, -541 octal buffer/line drivers use the RCA ADVANCED CMOS technology. The CD54/74AC/ACT540 are inverting 3-state buffers having two active-LOW output enables. The CD54/74AC/ACT541 are non-inverting 3-state buffers having two active-LOW output enables.

The CD74AC540, -541, and CD74ACT540, -541 are supplied in 20-lead dual-in-line plastic packages (E suffix) and in 20-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Industrial (–40 to +85°C) and Extended Industrial/Military (–55 to +125°C).

The CD54AC540, -541, and CD54ACT540, -541, available in chip form (H suffix), are operable over the -55 to +125°C temperature range.

Family Features:

- Exceeds 2-kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-resistant CMOS process and circuit design
- Speed of bipolar FAST®/AS/S with significantly reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply.
- ± 24-mA output drive current
 - Fanout to 15 FAST® ICs
 - Drives 50-ohm transmission lines

TRUTH TABLE

| | CD54/74AC/ACT540 | | | | | | | | |
|----------|------------------|---------|--|--|--|--|--|--|--|
| INPUTS | | OUTPUTS | | | | | | | |
| ŌE1, ŌE2 | Α | Υ | | | | | | | |
| L | L | Н | | | | | | | |
| L | н | L | | | | | | | |
| н | Х | _ Z | | | | | | | |

TRUTH TABLE

| | CD54/74AC/ACT541 | | | | | | | | | |
|----------|------------------|---------|--|--|--|--|--|--|--|--|
| INPUTS | | OUTPUTS | | | | | | | | |
| OE1, OE2 | Α | Υ | | | | | | | | |
| L | L | L | | | | | | | | |
| L | н | Н | | | | | | | | |
| н | X | Z | | | | | | | | |

H = High Voltage

L = Low Voltage

X = Immaterial

Z = High Impedance

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| MAXIMUM RATINGS, Absolute-Maximum Values: | |
|---|---------------|
| DC SUPPLY-VOLTAGE (V _{CC}) | –0.5 to 6 V |
| DC INPUT DIODE CURRENT, $I_{ K }$ (for $V_{ } < -0.5$ or $V_{ } > V_{CC} + 0.5$ V) | ±20 mA |
| DC OUTPUT DIODE CURRENT, I_{OK} (for $V_O < -0.5$ or $V_O > V_{CC} + 0.5$ V) | ±50 mA |
| DC OUTPUT SOURCE OR SINK CURRENT per Output Pin, IO (for VO > -0.5 or VO < VCC + 0.5 V) | ±50 mA |
| DC V _{CC} OR GROUND CURRENT (I _{CC} or I _{GND}) | ±100 mA* |
| PACKAGE THERMAL IMPEDANCE, θJA (see Note 1): E package | 69°C/W |
| M package | 58°C/W |
| STORAGE TEMPERATURE (T _{stq}) | –65 to +150°C |
| LEAD TEMPERATURE (DURINĞ SOLDERING): | |
| At distance 1/16 \pm 1/32 in. (1.59 \pm 0.79 mm) from case for 10 s maximum | +265°C |
| Unit inserted into PC board min. thickness 1/16 in. (1.59 mm) with solder contacting lead tips only | +300°C |
| * For up to 4 outputs per device; add +25 mA for each additional output | |

RECOMMENDED OPERATING CONDITIONS:

For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

| CHARACTERICTIC | LIM | LIMITS | | | | |
|---|-------------|----------------|----------------------|--|--|--|
| CHARACTERISTIC | MIN. | MAX. | UNITS | | | |
| Supply-Voltage Range, V _{cc} *: (For T _A = Full Package-Temperature Range) AC Types ACT Types | 1.5 4.5 | 5.5 5.5 | V | | | |
| DC Input or Output Voltage, V _I , V _O | 0 | Vcc | V | | | |
| Operating Temperature, T _A : | -55 | +125 | °C | | | |
| Input Rise and Fall Slew Rate, dt/dv at 1.5 V to 3 V (AC Types) at 3.6 V to 5.5 V (AC Types) at 4.5 V to 5.5 V (ACT Types) | 0 0 0 | 50 20 10 | ns/V ns/V ns/V | | | |

^{*}Unless otherwise specified, all voltages are referenced to ground.

TERMINAL ASSIGNMENT DIAGRAMS



NOTE 1: The package thermal impedance is calculated in accordance with JESD 51.

| Technical Data _ | |
|------------------|--|
|------------------|--|

STATIC ELECTRICAL CHARACTERISTICS: AC Series

| | | | | | | AMBIENT | TEMPE | RATURE | (T _A) - °(| | | | | |
|----------------------------------|-----------------|----------------------------------|------------------------|-----------------|------|---------|--------|--------|------------------------|------|-------|--|---|---|
| CHARACTERISTIC | cs | TEST CONDITIONS | | V _{cc} | +: | 25 | -40 to | o +85 | -55 to | +125 | UNITS | | | |
| | | V, (V) | I _o (mA) | (v) | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | | | | |
| High-Level Input | | | , | 1.5 | 1.2 | _ | 1.2 | | 1.2 | | | | | |
| Voltage | V _{iH} | | | 3 | 2.1 | _ | 2.1 | _ | 2.1 | | V | | | |
| | | | | 5.5 | 3.85 | _ | 3.85 | l – | 3.85 | | l | | | |
| Low-Level Input | | | | 1.5 | | 0.3 | _ | 0.3 | - | 0.3 | | | | |
| Voltage | VIL | : | | 3 | | 0.9 | _ | 0.9 | - | 0.9 | V | | | |
| | | | | 5.5 | - | 1.65 | _ | 1.65 | | 1.65 |] | | | |
| High-Level Output | | | -0.05 | 1.5 | 1.4 | _ | 1.4 | | 1.4 | _ | | | | |
| Voltage | V_{OH} | V _{IH} | -0.05 | - 3 | 2.9 | _ | 2.9 | | 2.9 | | | | | |
| | | or | -0.05 | 4.5 | 4.4 | _ | . 4.4 | _ | 4.4 | _ | 1 | | | |
| | | VIL | -4 | 3 | 2.58 | _ | 2.48 | | 2.4 | _ |] v | | | |
| | | | -24 | 4.5 | 3.94 | _ | 3.8 | _ | 3.7 | |] | | | |
| | | " " 1 | -75 | 5.5 | | | 3.85 | | _ | |] | | | |
| | | #, * } | -50 | 5.5 | _ | | _ | | 3.85 | | | | | |
| Low-Level Output | | , | 0.05 | 1.5 | | 0.1 | | 0.1 | _ | 0.1 | | | | |
| Voltage | V_{OL} | VIH | 0.05 | 3 | _ | 0.1 | _ | 0.1 | | 0.1 | 1 | | | |
| | | or | 0.05 | 4.5 | _ | 0.1 | _ | 0.1 | _ | 0.1 | 1 | | | |
| | | Vil | 12 | 3 | | 0.36 | _ | 0.44 | _ | 0.5 | V | | | |
| | | | 24 | 4.5 | _ | 0.36 | _ | 0.44 | | 0.5 | 1 | | | |
| | | | | | (| 75 | 5.5 | _ | | _ | 1.65 | | _ |] |
| | | #. * } | 50 | 5.5 | _ | | _ | _ | | 1.65 | 1 | | | |
| Input Leakage Current | l _i | V _{cc} or GND | | 5.5 | _ | ±0.1 | _ | ±1 | - | ±1 | μΑ | | | |
| 3-State Leakage Current | loz | V _{IH} | | | | | | | | | | | | |
| | | V _{IL} V _O = | | 5.5 | _ | ±0.5 | _ | ±5 | _ | ±10 | μΑ | | | |
| | | or GND | | | | | | | | | | | | |
| Quiescent Supply Current, MSI | Icc | V _∞ or GND | 0 | 5.5 | _ | 8 | _ | 80 | _ | 160 | μΑ | | | |

[#]Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize

power dissipation.

* Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

STATIC ELECTRICAL CHARACTERISTICS: ACT Series

| | | | | AMBIENT TEMPERATURE (TA) - °C | | | | | |] | |
|---|-----------------|----------------------------------|------------------------|-------------------------------|------|------|------|-------|--------|------|-------|
| CHARACTERIST | ICS | TEST CONDITIONS | | V _{cc} | + | +25 | | o +85 | -55 to | +125 | UNITS |
| | | V, (V) | I _o (mA) | (V) | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. |] |
| High-Level Input Voltage | ViH | | | 4.5 to 5.5 | 2 | _ | 2 | _ | 2 | _ | v |
| Low-Level Input Voltage | VIL | | | 4.5 to 5.5 | | 0.8 | | 0.8 | _ | 0.8 | v |
| High-Level Output | | ViH | -0.05 | 4.5 | 4.4 | _ | 4.4 | | 4.4 | | |
| Voltage | V _{OH} | or V _{IL} | -24 | 4.5 | 3.94 | | 3.8 | | 3.7 | | v |
| | | #, * { | -75 | 5.5 | _ | | 3.85 | | _ | |] . |
| | | " | -50 | 5.5 | | _ | _ | | 3.85 | _ | |
| Low-Level Output | | ViH | 0.05 | 4.5 | _ | 0.1 | | 0.1 | | 0.1 | |
| Voltage | Vol | or V _{IL} | 24 | 4.5 | | 0.36 | | 0.44 | _ | 0.5 | v |
| | | #. * } | 75 | 5.5 | | | _ | 1.65 | | |] ` |
| | | ···) | 50 | 5.5 | | | | | | 1.65 | |
| Input Leakage Current | l, | V _{CC} or GND | | 5.5 | _ | ±0.1 | _ | ±1 | | ±1 | μА |
| 3-State Leakage Current | loz | VIH or VIL Vo = Vcc or GND | | 5.5 | _ | ±0.5 | | ±5 | _ | ±10 | μΑ |
| Quiescent Supply Current, MSI | lcc | V _{cc} or GND | 0 | 5.5 | _ | 8 | _ | 80 | | 160 | μΑ |
| Additional Quiescent Current per Input P TTL Inputs High 1 Unit Load | | V _{cc} -2.1 | | 4.5 to 5.5 | | 2.4 | | 2.8 | | 3 | mA |

[#]Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

* Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

ACT INPUT LOADING TABLE

| INPUT | UNIT LOAD* | | | | | |
|----------|------------|-----|--|--|--|--|
| | 540 | 541 | | | | |
| DATA | 1.42 | 0.5 | | | | |
| OE1, OE2 | 1.3 | 1.3 | | | | |

*Unit load is Δl_{CC} limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25° C.

SWITCHING CHARACTERISTICS: AC Series; t,, t, = 3 ns, C, = 50 pF

| | | | AMBI | ENT TEMPE | RATURE (1 | Γ _A) - °C | |
|---|--------------------------------------|-------------------|----------------|---------------------|---------------|-----------------------|-------|
| CHARACTERISTICS | SYMBOL | (vs | -40 1 | lo +85 | -55 to | o +125 | UNITS |
| | 1 1 | (*) | MIN. | MAX. | MIN. | MAX. | } |
| Propagation Delays: Data to Output AC540 | tpLH tpHL | 1.5 3.3* 5† | 2.4 1.8 | 77 8.6 6.2 | 2.4 1.7 | 85 9.5 6.8 | ns |
| AC541 | t _{PLH} t _{PHL} | 1.5 3.3 5 | 2.8 2.1 | 89 9.9 7.1 | 2.7 2 | 98 10.9 7.8 | ns |
| Enable, to Output to Output | t _{PZL} t _{PZH} | 1.5 3.3 5 | 4.6 3.1 | 136 16.4 10.9 | - 4.5 3 | 150 18 12 | ns |
| Disable to Output to Output | t _{PLZ} t _{PHZ} | 1.5 3.3 5 | 3.9 3.1 | 136 13.6 10.9 | 3.8 3 | 150 15 12 | ns |
| Power Dissipation Capacitance AC540 AC541 | C _{PD} ‡ | | | Тур. Тур. | | Тур. Тур. | pF |
| Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching) | V _{онv} See Fig. 1 | 5 | | V | | | |
| Max. (Peak) Vol. During Switching of Other Outputs (Output Under Test Not Switching) | V _{OLP} See Fig. 1 | 5 | 1 Typ. @ 25°C | | | V | |
| Input Capacitance | Cı | _ | _ | 10 | _ | 10 | pF |
| 3-State Output Capacitance | Co | _ | <u> </u> | 15 | | 15 | pF |

SWITCHING CHARACTERISTICS: ACT Series; t,, t, = 3 ns, C, = 50 pF

| | | | AMBI | AMBIENT TEMPERATURE (TA) - °C | | | | | |
|---|--------------------------------------|-----------------|---------------|---------------------------------|--------|------|-------|--|--|
| CHARACTERISTICS | SYMBOL | V _{cc} | -40 | o +85 | -55 to | =125 | UNITS | | |
| | | (V) | MIN. | MAX. | MIN. | MAX. |] | | |
| Propagation Delays: Data to Output ACT540 | tpLH tpHL | 5† | 1.9 | 6.5 | 1.8 | 7.2 | ns | | |
| ACT541 | t _{PLH} t _{PHL} | 5† | 2.1 | 7.5 | 2.1 | 8.2 | ns | | |
| Enable to Output | t _{PZL} t _{PZH} | 5 | 3.5 | 12.2 | 3.4 | 13.4 | ns | | |
| Disable to Output | t _{PLZ} t _{PHZ} | 5 | 3.5 | 12.2 | 3.4 | 13.4 | ns | | |
| Power Dissipation Capacitance ACT540 ACT541 | C _{PO} § | - | | 60 Typ. 60 Typ. 60 Typ. 60 Typ. | | | pF | | |
| Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching) | V _{онv} See Fig. 1 | 5 | | ٧ . | | | | | |
| Max. (Peak) V _{OL} During Switching of Other Outputs (Output Under Test Not Switching) | V _{OLP} See Fig. 1 | 5 | 1 Typ. @ 25°C | | | v | | | |
| Input Capacitance | Cı | _ | T - | 10 | _ | 10 | pF | | |
| 3-State Output Capacitance | Co | . – | _ | 15 | _ | 15 | pF | | |

*3.3 V: min. is @ 3.6 V max. is @ 3 V

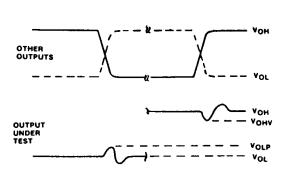
§C_{PD} is used to determine the dynamic power consumption, per channel.

For AC series, $P_D = V_{cc}^2 f_i (C_{PD} + C_L)$ For ACT series, $P_D = V_{cc}^2 f_i (C_{PD} + C_L) + V_{cc} \Delta I_{cc}$ where

f_i = input frequency C_L = output load capacitance

 V_{CC} = supply voltage.

PARAMETER MEASUREMENT INFORMATION



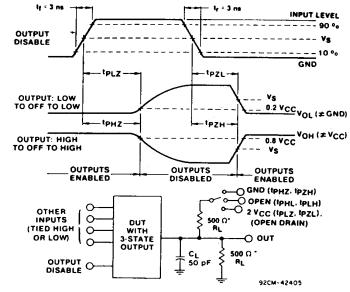
NOTES:

- 1. VOHY AND VOLP ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST.

 2. INPUT PULSES HAVE THE FOLLOWING CHARACTERISTICS:
- PRR ≤ 1 MHz, t₇ = 3 ns, t₁ = 3 ns, SKEW 1 ns.

 3. R.F. FIXTURE WITH 700-MHz DESIGN RULES REQUIRED.
 IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED WITH 0.1 pF CAPACITOR. SCOPE AND PROBES REQUIRE 700-MHz BANDWIDTH.

9205-42406



*FOR AC SERIES ONLY: WHEN v_{CC} = 1.5 V, r_L = 1 $k\Omega$

Fig. 1 - Simultaneous switching transient waveforms.

Fig. 2 - Three-state propagation delay waveforms and test circuit.

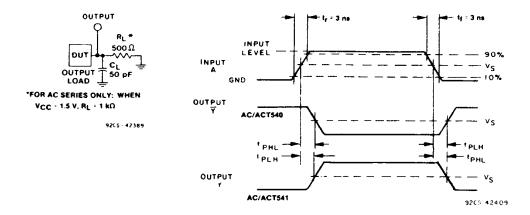


Fig. 3 - Propagation delay times and test circuit.

| | CD54/74AC | CD54/74ACT |
|--|---------------------|---------------------|
| Input Level | V _{cc} | 3 V |
| Input Switching Vottage, Vs | 0.5 V _{cc} | 1.5 V |
| Output Switching Voltage, V ₅ | 0.5 V _{CC} | 0.5 V _{cc} |





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PACKAGING INFORMATION

| Orderable Device | Status | Package Type | Package | Pins | Package | Eco Plan | Lead/Ball Finish | MSL Peak Temp | Op Temp (°C) | Device Marking | Samples |
|------------------|--------|--------------|---------|------|---------|----------------------------|------------------|--------------------|--------------|----------------|---------|
| | (1) | | Drawing | | Qty | (2) | (6) | (3) | | (4/5) | |
| CD54AC541F3A | ACTIVE | CDIP | J | 20 | 1 | TBD | A42 | N / A for Pkg Type | -55 to 125 | CD54AC541F3A | Samples |
| CD54ACT540F3A | ACTIVE | CDIP | J | 20 | 1 | TBD | A42 | N / A for Pkg Type | -55 to 125 | CD54ACT540F3A | Samples |
| CD54ACT541F3A | ACTIVE | CDIP | J | 20 | 1 | TBD | A42 | N / A for Pkg Type | -55 to 125 | CD54ACT541F3A | Samples |
| CD74AC540M | ACTIVE | SOIC | DW | 20 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC540M | Samples |
| CD74AC540M96 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | | AC540M | Samples |
| CD74AC540ME4 | ACTIVE | SOIC | DW | 20 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC540M | Samples |
| CD74AC541E | ACTIVE | PDIP | N | 20 | 20 | Pb-Free (RoHS) | CU NIPDAU | N / A for Pkg Type | -55 to 125 | CD74AC541E | Samples |
| CD74AC541EE4 | ACTIVE | PDIP | N | 20 | 20 | Pb-Free (RoHS) | CU NIPDAU | N / A for Pkg Type | -55 to 125 | CD74AC541E | Samples |
| CD74AC541M | ACTIVE | SOIC | DW | 20 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC541M | Samples |
| CD74AC541M96 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC541M | Samples |
| CD74AC541M96E4 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC541M | Samples |
| CD74AC541M96G4 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC541M | Samples |
| CD74AC541MG4 | ACTIVE | SOIC | DW | 20 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC541M | Samples |
| CD74AC541SM96 | ACTIVE | SSOP | DB | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC541SM | Samples |
| CD74AC541SM96G4 | ACTIVE | SSOP | DB | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | AC541SM | Samples |
| CD74ACT540E | ACTIVE | PDIP | N | 20 | 20 | Pb-Free (RoHS) | CU NIPDAU | N / A for Pkg Type | -55 to 125 | CD74ACT540E | Samples |
| CD74ACT540EE4 | ACTIVE | PDIP | N | 20 | 20 | Pb-Free (RoHS) | CU NIPDAU | N / A for Pkg Type | -55 to 125 | CD74ACT540E | Samples |





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| Orderable Device | Status | Package Type | Package | Pins | Package | Eco Plan | Lead/Ball Finish | MSL Peak Temp | Op Temp (°C) | Device Marking | Samples |
|------------------|--------|--------------|---------|------|---------|----------------------------|------------------|--------------------|--------------|----------------|---------|
| | (1) | | Drawing | | Qty | (2) | (6) | (3) | | (4/5) | |
| CD74ACT540M | ACTIVE | SOIC | DW | 20 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT540M | Samples |
| CD74ACT540M96 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT540M | Samples |
| CD74ACT540M96G4 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT540M | Samples |
| CD74ACT540MG4 | ACTIVE | SOIC | DW | 20 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT540M | Samples |
| CD74ACT541E | ACTIVE | PDIP | N | 20 | 20 | Pb-Free (RoHS) | CU NIPDAU | N / A for Pkg Type | -55 to 125 | CD74ACT541E | Samples |
| CD74ACT541EE4 | ACTIVE | PDIP | N | 20 | 20 | Pb-Free (RoHS) | CU NIPDAU | N / A for Pkg Type | -55 to 125 | CD74ACT541E | Samples |
| CD74ACT541M | ACTIVE | SOIC | DW | 20 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT541M | Samples |
| CD74ACT541M96 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT541M | Samples |
| CD74ACT541M96E4 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT541M | Samples |
| CD74ACT541M96G4 | ACTIVE | SOIC | DW | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT541M | Samples |
| CD74ACT541MG4 | ACTIVE | SOIC | DW | 20 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT541M | Samples |
| CD74ACT541SM96 | ACTIVE | SSOP | DB | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT541SM | Samples |
| CD74ACT541SM96E4 | ACTIVE | SSOP | DB | 20 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM | -55 to 125 | ACT541SM | Samples |

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.





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Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD54AC541, CD54ACT540, CD54ACT541, CD74AC541, CD74ACT540, CD74ACT541:

- Catalog: CD74AC541, CD74ACT540, CD74ACT541
- Military: CD54AC541, CD54ACT540, CD54ACT541

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





| | Dimension designed to accommodate the component width |
|----|---|
| | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

| Device | Package Type | Package Drawing | | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|----------------|-----------------|--------------------|----|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| CD74AC540M96 | SOIC | DW | 20 | 2000 | 330.0 | 24.4 | 10.8 | 13.3 | 2.7 | 12.0 | 24.0 | Q1 |
| CD74AC541M96 | SOIC | DW | 20 | 2000 | 330.0 | 24.4 | 10.8 | 13.3 | 2.7 | 12.0 | 24.0 | Q1 |
| CD74AC541SM96 | SSOP | DB | 20 | 2000 | 330.0 | 16.4 | 8.2 | 7.5 | 2.5 | 12.0 | 16.0 | Q1 |
| CD74ACT540M96 | SOIC | DW | 20 | 2000 | 330.0 | 24.4 | 10.8 | 13.3 | 2.7 | 12.0 | 24.0 | Q1 |
| CD74ACT541M96 | SOIC | DW | 20 | 2000 | 330.0 | 24.4 | 10.8 | 13.3 | 2.7 | 12.0 | 24.0 | Q1 |
| CD74ACT541SM96 | SSOP | DB | 20 | 2000 | 330.0 | 16.4 | 8.2 | 7.5 | 2.5 | 12.0 | 16.0 | Q1 |

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*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|----------------|--------------|-----------------|------|------|-------------|------------|-------------|
| CD74AC540M96 | SOIC | DW | 20 | 2000 | 367.0 | 367.0 | 45.0 |
| CD74AC541M96 | SOIC | DW | 20 | 2000 | 367.0 | 367.0 | 45.0 |
| CD74AC541SM96 | SSOP | DB | 20 | 2000 | 367.0 | 367.0 | 38.0 |
| CD74ACT540M96 | SOIC | DW | 20 | 2000 | 367.0 | 367.0 | 45.0 |
| CD74ACT541M96 | SOIC | DW | 20 | 2000 | 367.0 | 367.0 | 45.0 |
| CD74ACT541SM96 | SSOP | DB | 20 | 2000 | 367.0 | 367.0 | 38.0 |

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



14 LEADS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

DB (R-PDSO-G**)

PLASTIC SMALL-OUTLINE

28 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-150

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